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| Notice of References Cited | Application/Control No. 10/574,253 | | Applicant(s)/Patent Under Reexamination MORIMOTO, HIDEO | |
| | Examiner PUNAM PATEL | | Art Unit 2855 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-5,948,996 A | 09-1999 | Takeuchi et al. | 73/862.043 |
| * | B | US-5,959,209 A | 09-1999 | Takeuchi et al. | 73/514.34 |
| * | C | US-6,642,594 B2 | 11-2003 | Kurtz, Anthony D. | 257/419 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | Wiley Encyclopedia of Electrical and Electronics Engineering: Strain Sensors, © 1999 pp 566-580 |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.